

Entrusted Items Concerning Preparation of Draft Proposals for JIS

Newly Established

Divisional Council	T i t l e	Assigned Organization	Contact
Civil Engineering	Brick for pavement	Japan Bricks Association	A
Iron and Steel	Classification – Surface insulations of electrical steel sheet, strip and laminations	The Japan Electrical Manufacturers' Association	A
Non-Ferrous Metals	Anodizing of aluminium and its alloys – Measurement of abrasion resistance of anodic oxidation coatings	Japan Aluminium Products Association	A
Basic Engineering	Vacuum Technology – Vacuum gauges – Specifications for hot cathode ionization gauges	The Vacuum Society of Japan	A
Chemical Products	Plastics – Determination of scratch properties	The Japan Plastics Industry Federation	A
Testing and Measurement Technology	Method of continuous dust monitoring in flue gas from stationary sources	Japan Electric Measuring Instruments Manufacturers' Association	A
Testing and Measurement Technology	Safety requirements for electrical equipment for measurement, control, and laboratory use – Part 2-30 : Particular requirements for testing and measuring circuits	Japan Electric Measuring Instruments Manufacturers' Association	A
Industrial Machinery	Safety requirements of resistance heating furnace	Japan Industrial Furnace Manufacturers Association	A
Industrial Machinery	Main dimensions of the auto hitch on the standard three-point hitch of agricultural wheel tractors	Japan Farm Machinery Manufacturer's Association	A
Medical Equipment	Dentistry—Root-canal instruments – Part 1:General requirements and test methods	Japan Dental Machine Manufacturers Association	B
Medical Equipment	Dentistry—Root-canal instruments -- Part 3: Condensers, pluggers and spreaders	Japan Dental Machine Manufacturers Association	B
Medical Equipment	Dentistry—Laser welding	Japan Dental Machine Manufacturers Association	B
Medical Equipment	Dentistry—Implants—Dynamic fatigue test for endosseous dental implants	Japan Dental Machine Manufacturers Association	B
Electrial Technology	Electromagnetic compatibility (EMC) – Part 4-22: Testing and measurement techniques – Radiated emissions and immunity measurements in fully anechoic rooms (FARs)	The Institute of Electrical Engineers of Japan	B

Electrial Technology	Tests and Requirements of Safety for Secondary Lithium Cells and Batteres, for use in Industrial Applications	Battery Assosiation of Japan	B
Electronics	Time relays for industrial and residential use – Part 1: Requirements and tests	Nipon Electric Control Equipment Industries Association	C
Electronics	Semiconductor devices–Micro–electromechanical devices–Part 12:Bending fatigue testing method of thin film materials using resonant vibration of MEMS structures	Micromachine Center	C
Electronics	Connectors for electronic equipment – Tests and measurements –Part 15–2: Connector tests (mechanical) –Test 15b: Insert retention in housing (axial)	Japan Electronics & Information Tecnology Industories Association	C
Electronics	Connectors for electronic equipment – Tests and measurements –Part 15–3: Connector tests (mechanical) –Test 15c: Insert retention in housing	Japan Electronics & Information Tecnology Industories Association	C
Electronics	Connectors for electronic equipment – Tests and measurements –Part 15–5: Connector tests (mechanical) –Test 15e: Contact retention in insert, cable nutation	Japan Electronics & Information Tecnology Industories Association	C
Electronics	Connectors for electronic equipment – Tests and measurements –Part16–1: Mechanical tests on contacts and terminations –Test 16a : Probe damage	Japan Electronics & Information Tecnology Industories Association	C
Electronics	Connectors for electronic equipment – Tests and measurements –Part 16–6: Mechanical tests on contacts and terminations –Test 16f: Robustness of terminations	Japan Electronics & Information Tecnology Industories Association	C
Electronics	Non–connectorized single–mode fibre optics middle–scale 1xN DWDM devices	Optoelectronics Industry and Technology Development Association	C
Electronics	Fiber optic chromatic dispersion compensator using single–mode dispersion compensating fiber	Optoelectronics Industry and Technology Development Association	C
Electronics	Fiber optic connector interfaces – Part 6–1: Type MU connector family – Simplified receptacle MU–PC connector interfaces (Type F17)	Optoelectronics Industry and Technology Development Association	C
Electronics	Fibre optic interconnecting devices and passive components – Basic test and measurement procedures – Part 3–1: Visual examination	Optoelectronics Industry and Technology Development Association	C
Electronics	Fiber optic interconnecting devices and passive components – Basic test and measurement procedures – Part 3–17: Examinations and measurements – Endface angle of angle–polished ferrules	Optoelectronics Industry and Technology Development Association	C
Electronics	Fiber optic interconnecting devices and passive components – Basic test and measurement procedures – Part 3–23: Examination and measurements – Fiber position relative to ferrule endface	Optoelectronics Industry and Technology Development Association	C
Electronics	Optical amplifiers – Test methods – Part 4–1:Transient parameters – Two–wavelength method	Optoelectronics Industry and Technology Development Association	C

Electronics	Optical amplifiers – Test methods – Part 4-2:Transient parameters – Broadband source method	Optoelectronics Industry and Technology Development Association	C
Electronics	Optical amplifiers – Part 6-1: Interfaces – Command set	Optoelectronics Industry and Technology Development Association	C
Electronics	Fiber optic communication subsystem test procedures – Part2-3:Digital systems – Jitter and wander measurements	Optoelectronics Industry and Technology Development Association	C
Electronics	Calibration of optical time-domain reflectometers (OTDR) – Part 1: OTDR for single mode fibers	Optoelectronics Industry and Technology Development Association	C
Electronics	Calibration of optical time-domain reflectometers (OTDR) – Part 2: OTDR for multimode fibers	Optoelectronics Industry and Technology Development Association	C
Information Technology	Information technology -- Automatic identification and data capture techniques -- Bar code print quality test specification -- Tow-dimantional	Japan Automatic Identification Systems Association	C
Information Technology	Integrated circuit cards – Enhanced terminal accessibility using cardholder preference interface	Japan IC Card System Application Council	C